Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/669,184	LEMKE ET AL.	
Examiner	Art Unit	
Alan S. Chen	2182	

SEARCHED			
Class	Subclass	Date	Examiner
710	9	5117165	ASL
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713	1		
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARCH		·)
-	DATE	EXMR
(EAST) USPAT; USPGPUB; EPO; JPO; IBM_TDB; DERWENT	5117105	ASC